Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/666,462	STONE ET AL.
Examiner	Art Unit
Hae M. Hyeon	2839

SEARCHED									
Class	Subclass	Date	Examiner						
439	70	3/06	hanh						
439	71								
439	342								
439	264								
439	68	V							

INT	INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner			

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